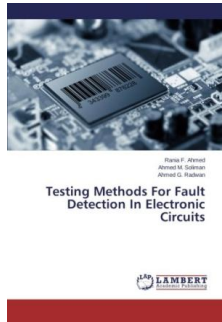


Find Doc

TESTING METHODS FOR FAULT DETECTION IN ELECTRONIC CIRCUITS



LAP Lambert Academic Publishing Dez 2014, 2014. Taschenbuch. Book Condition: Neu. 220x150x11 mm. Neuware - This book includes two testing methodologies based on Built In Sensors (BIS) and an optimization-based technique. The first part proposes two novel built-in sensors (BISs) for digital CMOS and analog circuits testing. The BISs have no voltage degradation, able to detect, identify and localize open and short circuit faults, have simple realizations with very small area and detection time. BIS is used to test a 4x4...

Download PDF Testing Methods For Fault Detection In Electronic Circuits

- Authored by Rania F. Ahmed
- Released at 2014

[DOWNLOAD](#)


Filesize: 6.09 MB

Reviews

This book is indeed gripping and fascinating. It normally is not going to price a lot of. I am very easily will get a delight of reading a created pdf.
-- **Albertha Cartwright**

A fresh e book with a new viewpoint. It is among the most awesome ebook we have read through. Once you begin to read the book, it is extremely difficult to leave it before concluding.
-- **Prof. Christelle Stark III**

The most effective book i ever read. I really could comprehended almost everything out of this published e ebook. You wont truly feel monotony at at any time of your respective time (that's what catalogs are for regarding should you ask me).
-- **Rusty Kerluke**